Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination	
09663968	YIP, PING	
Examiner	Art Unit	
Skowronek, Karlheinz R	1631	

SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES					
Search Notes	Date	Examiner			
Search Terms: MASS SPEC, DATA ANALYSIS, AUTOMATED, COMPUTER, DENOISE, WAVELET TRANSFORMATION, RESIDUAL BASELINE, MOVING AVERAGE BASELINE, DNA, TIME OF FLIGHT, NOISE REMOVAL, PEAK SUBTRACTION; Inventor search	4/4/2007	KRS			
EAST:Search Terms, See Attached	4/4/2007	KRS			
STN:MEDLINE, CAPLUS, BIOSIS,EMBASE,PASCAL,SCISEARCH; Search Terms	4/4/2007	KRS			

INTERFERENCE SEARCH					
Class	Subclass	Date	Examiner		
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Part of Paper No.: 20060908